

FCC CFR47 PART 15 SUBPART C

NFC

CERTIFICATION TEST REPORT

FOR

GSM/WCDMA/LTE Phone + BT/BLE, DTS/UNII a/b/g/n, ANT+ and NFC

MODEL NUMBER: SM-A710M/DS, SM-A710M

FCC ID: A3LSMA710M

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Prepared for

SAMSUNG ELECTRONICS CO., LTD. 129 SAMSUNG-RO, YEONGTONG-GU, SUWON-SI, GYEONGGI-DO, 16677, KOREA

Prepared by

UL Korea, Ltd. Suwon Laboratory 218 Maeyeong-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16675, Korea

TEL: (031) 337-9902 FAX: (031) 213-5433



Revision History

Rev.	Issue Date	Revisions	Revised By
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1. ATTESTATION OF TEST RESULTS

COMPANY NAME: SAMSUNG ELECTRONICS CO., LTD.

EUT DESCRIPTION: GSM/WCDMA/LTE Phone + BT/BLE, DTS/UNII a/b/g/n, ANT+ and NFC

MODEL NUMBER: SM-A710M/DS, SM-A710M

SERIAL NUMBER: 33002292a8a572b9 (RADIATED); R38GA0JTKBJ (CONDUCTED)

DATE TESTED: NOV 11, 2015 - NOV 25, 2015

APPLICABLE STANDARDS

STANDARD TEST RESULTS

CFR 47 Part 15 Subpart C Pass

UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government.

Approved & Released For UL Korea, Ltd. By:

Tested By:

CY Choi

Suwon Lab Engineer

The

UL Korea, Ltd.

Junwhan Lee Suwon Lab Engineer UL Korea, Ltd.

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2. TEST METHODOLOGY

The tests documented in this report were performed in accordance with ANSI C63.10-2009, FCC CFR 47 Part 2, FCC CFR 47 Part 15.

3. FACILITIES AND ACCREDITATION

The test sites and measurement facilities used to collect data are located at 218 Maeyeong-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16675, Korea. Line conducted emissions are measured only at the 218 address. The following table identifies which facilities were utilized for radiated emission measurements documented in this report. Specific facilities are also identified in the test results sections.

218 Maeyeong-ro

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637. The full scope of accreditation can be viewed at http://www.iasonline.org/PDF/TL/TL-637.pdf.

4. CALIBRATION AND UNCERTAINTY

4.1. MEASURING INSTRUMENT CALIBRATION

The measuring equipment utilized to perform the tests documented in this report has been calibrated in accordance with the manufacturer's recommendations, and is traceable to recognized national standards.

4.2. SAMPLE CALCULATION

Where relevant, the following sample calculation is provided:

Field Strength (dBuV/m) = Measured Voltage (dBuV) + Antenna Factor (dB/m) + Cable Loss (dB) – Preamp Gain (dB) 36.5 dBuV + 18.7 dB/m + 0.6 dB – 26.9 dB = 28.9 dBuV/m

4.3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the apparatus:

PARAMETER	UNCERTAINTY
Conducted Disturbance, 0.15 to 30 MHz	2.32 dB
Radiated Disturbance, Below 1GHz	4.14 dB

Uncertainty figures are valid to a confidence level of 95%.

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5. EQUIPMENT UNDER TEST

5.1. DESCRIPTION OF EUT

The EUT is GSM/WCDMA/LTE Phone + BT/BLE, DTS/UNII a/b/g/n, ANT+ and NFC. This test report addresses the DXX (NFC) operational mode.

SM-A710M and SM-A710M/DS are same hardware but for different number of SIM card slot. SM-A710M has one slot. SM-A710M/DS is dual SIM version.

The FCC ID: A3LSMA710M shares the same enclosure and circuit board as FCC ID: A3LSMA710F. The NFC circuitry and layout, including antennas, are almost identical between the two units. The NFC antennas and surrounding circuitry are the same between these two units.

After confirming through preliminary radiated emissions that the performance of the FCC ID: A3LSMA710F remains representative of FCC ID: A3LSMA710M, test data for FCC ID: A3LSMA710F is being submitted for this application to cover NFC features.

5.2. MAXIMUM OUTPUT POWER

The testing was performed at 1 meter. The transmitter maximum E-field at 30m distance is 16.99 dBuV/m which convert from 1 meter data.

5.3. WORST-CASE CONFIGURATION AND MODE

The NFC function was tested at its' fundamental and only operational frequency of 13.56 MHz. The fundamental of the EUT was investigated in three orthogonal orientations X, Y and Z. It was determined that the Z-orientation was the worst-case orientation; therefore all final radiated testing was performed with the EUT in the Z-orientation while generating continuous emissions.

5.4. MODIFICATIONS

No modifications were made during testing.

5.5. DESCRIPTION OF TEST SETUP

SUPPORT EQUIPMENT

Support Equipment List					
Description Manufacturer Model Serial Number I				FCC ID	
Charger	SAMSUNG	EP-TA20EWE	R37G8H02Q92SE3	N/A	
Data Cable	SAMSUNG	ECB-DU4AWE	N/A	N/A	
Earphone	SAMSUNG	EHS64AVFWE	N/A	N/A	

I/O CABLES

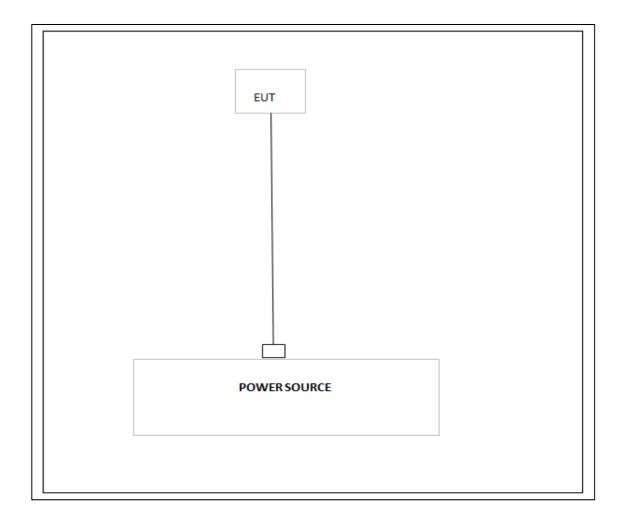
	I/O Cable List					
Cable No		# of identical ports	Connector Type	7.5	Cable Length (m)	Remarks
1	DC Power	1	Mini-USB	Shielded	0.8m	N/A
2	Audio	1	Mini-Jack	Unshielded	1.0m	N/A

TEST SETUP

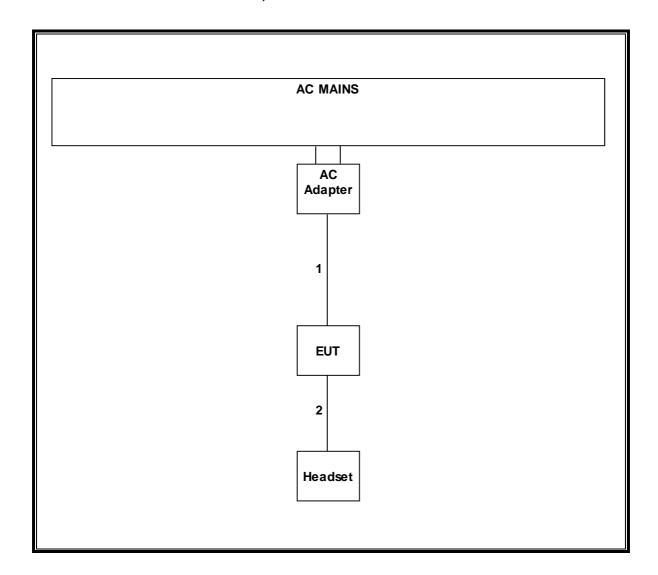
The EUT is a stand-alone device configured and tested in a worst-case setup. Note: worst case is using worst case orientation with AC charger and headset attached to the EUT with NFC signal continuously transmitting.

SETUP DIAGRAM FOR TESTS

Radiated Emissions Below 30 MHz:



Radiated Emissions Above 30 MHz, AC Line Conducted Emissions:



6. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was utilized for the tests documented in this report:

Test Equipment List					
Description	Manufacturer	Model	S/N	Cal Due	
Antenna, Bilog, 30MHz-1GHz	SCHWARZBECK	VULB9163	749	04-25-16	
Antenna, Loop, 9kHz-30MHz	R&S	HFH2-Z2	100418	11-18-15	
Preamplifier, 1000 MHz	Sonoma	310N	341282	08-18-16	
Spectrum Analyzer, 44 GHz	Agilent / HP	N9030A	MY54170614	08-19-16	
EMI Test Receive, 40 GHz	R&S	ESU40	100439	08-19-16	
DC Power Supply	Agilent / HP	E3640A	MY54226395	08-18-16	
Temperature Chamber	ESPEC	SH-642	93001109	08-18-16	
LISN	R&S	ENV216	101836	08-19-16	
LISN	R&S	ENV216	101837	08-19-16	

- NOTE: Loop Antenna HFH2-Z2(S/N: 100418) was utilized on Nov 11th 2015 for fundmental and spurious emission test (0.15 – 30 MHz)

FCC ID: A3LSMA710M

7. RADIATED EMISSION TEST RESULTS

7.1. LIMITS AND PROCEDURE

LIMIT

§15.225

- (a) The field strength of any emissions within the band 13.553–13.567 MHz shall not exceed 15.848 microvolts/ meter at 30 meters.
- (b) Within the bands 13.410–13.553 MHz and 13.567–13.710 MHz, the field strength of any emissions shall not exceed 334 microvolts/meter at 30 meters.
- (c) Within the bands 13.110–13.410 MHz and 13.710–14.010 MHz the field strength of any emissions shall not exceed 106 microvolts/meter at 30 meters.
- (d) The field strength of any emissions appearing outside of the 13.110–14.010 MHz and shall not exceed the general radiated emission limits in § 15.209 as follows: §15.209 (a) Except as provided elsewhere in this subpart, the emissions from an intentional radiator shall not exceed the field strength levels specified in the following table:

Limits for radiated disturbance of an intentional radiator				
Frequency range (MHz)	Limits (µV/m)	Measurement Distance (m)		
0.009 - 0.490	2400 / F (kHz)	300		
0.490 – 1.705	24000 / F (kHz)	30		
1.705 – 30.0	30	30		
30 – 88	100**	3		
88 - 216	150**	3		
216 – 960	200**	3		
Above 960	500	3		

^{**} Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g. §§ 15.231 and 15.241. §15.209 (b) In the emission table above, the tighter limit applies at the band edges.

Formula for converting the filed strength from uV/m to dBuV/m is: Limit $(dBuV/m) = 20 \log limit (uV/m)$

In addition:

§15.209 (d) The emission limits shown the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9-90 kHz, 110-490 kHz and above 1000 MHz. Radiated emissions limits in these three bands are based on measurements employing an average detector.

§15.209 (d) The provisions in §§ 15.225, measuring emissions at distances other than the distances specified in the above table, determining the frequency range over which radiated emissions are to be measured, and limiting peak emissions apply to all devices operated under this part.

TEST PROCEDURE

ANSI C63.10-2009

The EUT is an intentional radiator that incorporates a digital device. The highest fundamental frequency generated or used in the device is 13.56 MHz. The frequency range was investigated from 0.15 MHz to the 10th harmonic of the highest fundamental frequency, or 1000 MHz, whichever is greater (1000MHz)

RESULTS

No non-compliance noted:

7.1.1. FUNDAMENTAL AND SPURIOUS EMISSIONS (0.15 – 30 MHz)

RESULTS

Please refer to NFC test report of FCC ID: A3LSMA710F

7.1.2. TX SPURIOUS EMISSION 30 TO 1000 MHz

RESULTS

Please refer to NFC test report of FCC ID: A3LSMA710F

8. AC MAINS LINE CONDUCTED EMISSIONS

LIMITS

§15.207

(a) Except as shown in paragraphs (b) and (c) of this section, for an intentional radiator that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies, within the band 150 kHz to 30 MHz, shall not exceed the limits in the following table, as measured using a $50\mu H/50$ ohms line impedance stabilization network (LISN). Compliance with the provisions of this paragraph shall be based on the measurement of the radio frequency voltage between each power line and ground at the power terminal. The lower limit applies at the band edges.

Frequency range	Limits (dBμV)		
(MHz)	Quasi-peak	Average	
0.15 to 0.50	66 to 56	56 to 46	
0.50 to 5	56	46	
5 to 30	60	50	

Notes:

- 1. The lower limit shall apply at the transition frequencies
- 2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50 MHz.

TEST PROCEDURE

ANSI C63.10-2009

RESULTS

Please refer to NFC test report of FCC ID: A3LSMA710F

9. FREQUENCY STABILITY

LIMIT

§15.225 (e) The frequency tolerance of the carrier signal shall be maintained within ±0.01% of the operating frequency, over a temperature variation of -20 degrees to +50 degrees C at normal supply voltage, and for a variation in the primary supply voltage from 85% to 115% of the rated supply voltage at a temperature of 20 degrees C. For battery operated equipment, the equipment tests shall be performed using a new battery.

TEST PROCEDURE

ANSI C63.10 §6.8

RESULTS

Please refer to NFC test report of FCC ID: A3LSMA710F